

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Currently amended) An apparatus comprising:

an integrated circuit die;

an integrated circuit package coupled to the integrated circuit die;

mold compound in contact with the integrated circuit die and the integrated circuit package;

an first interconnect in contact with the integrated circuit package;

a second integrated circuit package; and

a second interconnect in contact with the second integrated circuit package,

wherein a first portion of the first interconnect is in contact with the mold compound, wherein a second portion of the first interconnect is not in contact with the mold compound, wherein the mold compound defines an opening, wherein the second portion of the first interconnect is recessed beneath the opening, wherein a third portion of the first interconnect is in contact with the integrated circuit package, and wherein the second interconnect is in contact with the first interconnect within the opening.

2. (Currently amended) An apparatus according to Claim 1, wherein the second portion is an upper portion of the first interconnect and the third portion is a lower portion of the first interconnect.

3. (Cancelled)

4. (Previously presented) An apparatus according to Claim 1, wherein the second integrated circuit package is in contact with the mold compound.

5. (Previously presented) An apparatus according to Claim 1 further comprising:
a second integrated circuit die in contact with the second integrated circuit package;
second mold compound in contact with the second integrated circuit die and the second integrated circuit package; and

a third interconnect coupled to the second integrated circuit package,
wherein a first portion of the third interconnect is in contact with the second mold compound, and wherein a second portion of the third interconnect is not in contact with the second mold compound, wherein the second mold compound defines a second opening, wherein the second portion of the third interconnect is recessed beneath the second opening, and wherein a third portion of the third interconnect is in contact with the second integrated circuit package.

6. (Previously presented) An apparatus according to Claim 5, further comprising:
a third integrated circuit package;
a fourth interconnect coupled to the third integrated circuit package,
wherein the fourth interconnect is coupled to the third interconnect within the second opening.

7. (Original) An apparatus according to Claim 1, further comprising:

a second integrated circuit die coupled to the integrated circuit die, in contact with the mold compound, and electrically coupled to the integrated circuit package.

8. (Currently amended) An apparatus comprising:

an integrated circuit package substrate;

a plurality of integrated circuit die coupled to the integrated circuit package substrate;

mold compound in contact with the plurality of integrated circuit die and the integrated circuit package substrate;

a first interconnect in contact with the integrated circuit package substrate and electrically coupled to one of the plurality of integrated circuit die;

a second integrated circuit package; and

a second interconnect in contact with the second integrated circuit package,

wherein a first portion of the first interconnect is in contact with the mold compound, wherein a second portion of the first interconnect is not in contact with the mold compound, wherein the mold compound defines an opening, wherein the second portion of the first interconnect is recessed beneath the opening, wherein a third portion of the first interconnect is in contact with the integrated circuit package substrate, and wherein the second interconnect is in contact with the first interconnect within the opening.

9. (Previously presented) An apparatus according to Claim 8, further comprising:

die attach material disposed between the first face of each of the plurality of integrated circuit die and the integrated circuit package substrate.

10. (Previously presented) An apparatus according to Claim 8, further comprising:

a second integrated circuit die in contact with the integrated circuit die, in contact with the mold compound, and electrically coupled to the integrated circuit package.

11. - 14. (Cancelled)

15. (Currently amended) A system comprising:

an integrated circuit die;

an integrated circuit package in contact with the integrated circuit die;

mold compound in contact with the integrated circuit die and the integrated circuit package; and

a first interconnect coupled to the integrated circuit package;

a second integrated circuit die;

a second integrated circuit package;

a second interconnect in contact with the second integrated circuit package; and

a double data rate memory electrically coupled to the integrated circuit die,

wherein a first portion of the first interconnect is in contact with the mold compound, wherein a second portion of the first interconnect is not in contact with the mold compound, wherein the mold compound defines an opening, wherein the second portion of the first interconnect is recessed beneath the opening, wherein a third portion of the first interconnect is in contact with the integrated circuit package, and wherein the second interconnect is in contact with the first interconnect within the opening.

16. (Cancelled)

17. (Previously presented) A system according to Claim 15, wherein the second integrated circuit package is in contact with the mold compound.

18. (Previously presented) A system according to Claim 15, further comprising:
a third integrated circuit die in contact with the integrated circuit die, in contact with the mold compound, and electrically coupled to the integrated circuit package.

19. (Original) A system according to Claim 15, further comprising:
a motherboard electrically coupled to the integrated circuit die and to the memory.